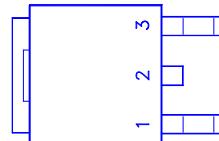
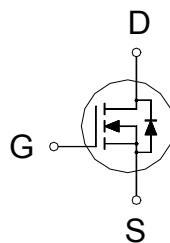


**NIKO-SEM**
**N-Channel Logic Level Enhancement  
Mode Field Effect Transistor**
**P6006BD  
TO-252  
Halogen-Free & Lead-Free**
**PRODUCT SUMMARY**

$V_{(BR)DSS}$	$R_{DS(ON)}$	$I_D$
60	60mΩ	22A


 1.GATE  
2.DRAIN  
3.SOURCE
**ABSOLUTE MAXIMUM RATINGS ( $T_C = 25^\circ\text{C}$  Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Drain-Source Voltage	$V_{DS}$	60	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current	$I_D$	21	A
		17	
Pulsed Drain Current <sup>1</sup>	$I_{DM}$	85	
Power Dissipation	$P_D$	50	W
		32	
Operating Junction & Storage Temperature Range	$T_j, T_{stg}$	-55 to 150	$^\circ\text{C}$
Lead Temperature ( $1/16$ " from case for 10 sec.)	$T_L$	275	

**THERMAL RESISTANCE RATINGS**

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$		2.5	$^\circ\text{C} / \text{W}$
Junction-to-Ambient	$R_{\theta JA}$		75	$^\circ\text{C} / \text{W}$

<sup>1</sup>Pulse width limited by maximum junction temperature.
**ELECTRICAL CHARACTERISTICS ( $T_C = 25^\circ\text{C}$ , Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu\text{A}$	60			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	1	1.5	2.5	
Gate-Body Leakage	$I_{GSS}$	$V_{DS} = 0V, V_{GS} = \pm 20V$			$\pm 250$	nA
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 48V, V_{GS} = 0V$			1	$\mu\text{A}$
		$V_{DS} = 40V, V_{GS} = 0V, T_J = 55^\circ\text{C}$			10	
On-State Drain Current <sup>1</sup>	$I_{D(\text{ON})}$	$V_{DS} = 5V, V_{GS} = 10V$	21			A

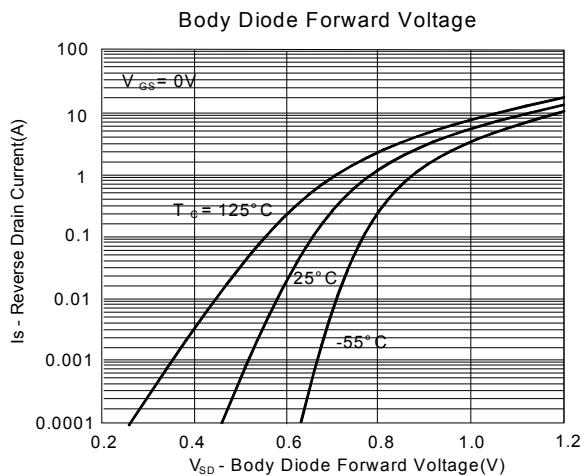
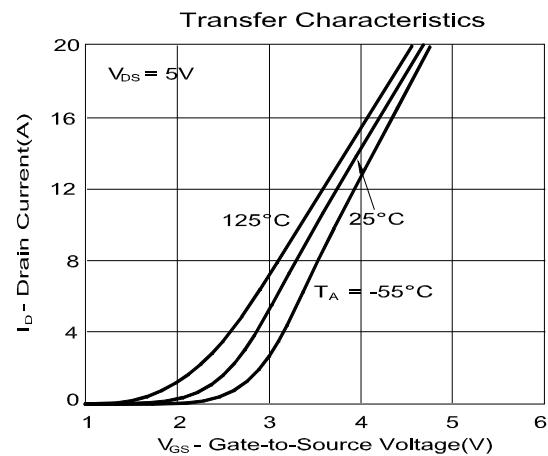
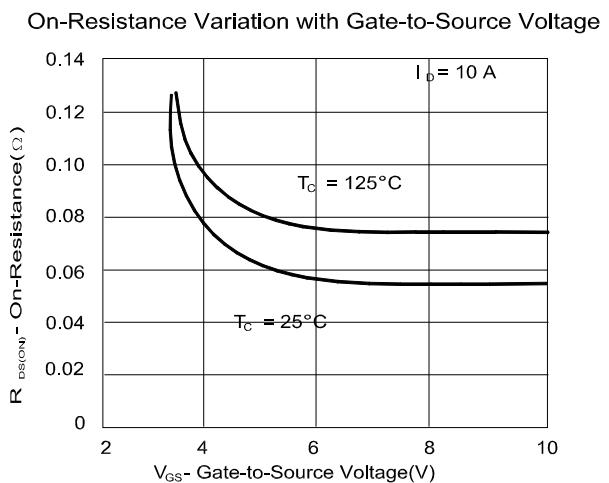
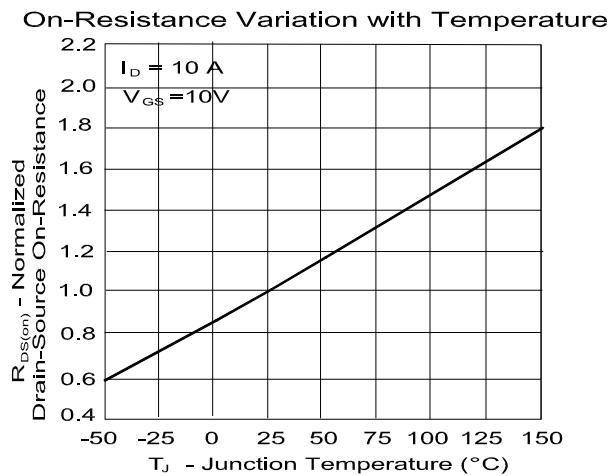
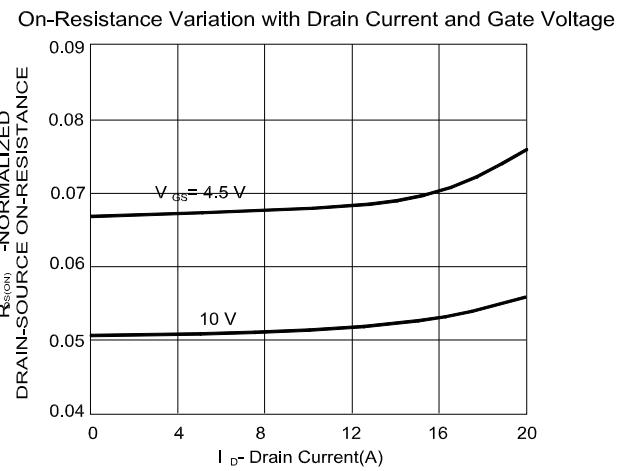
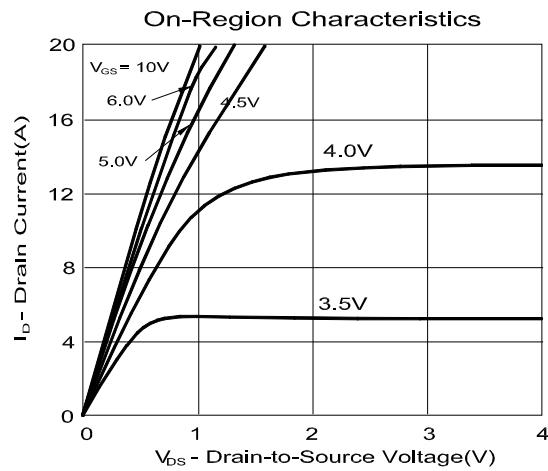
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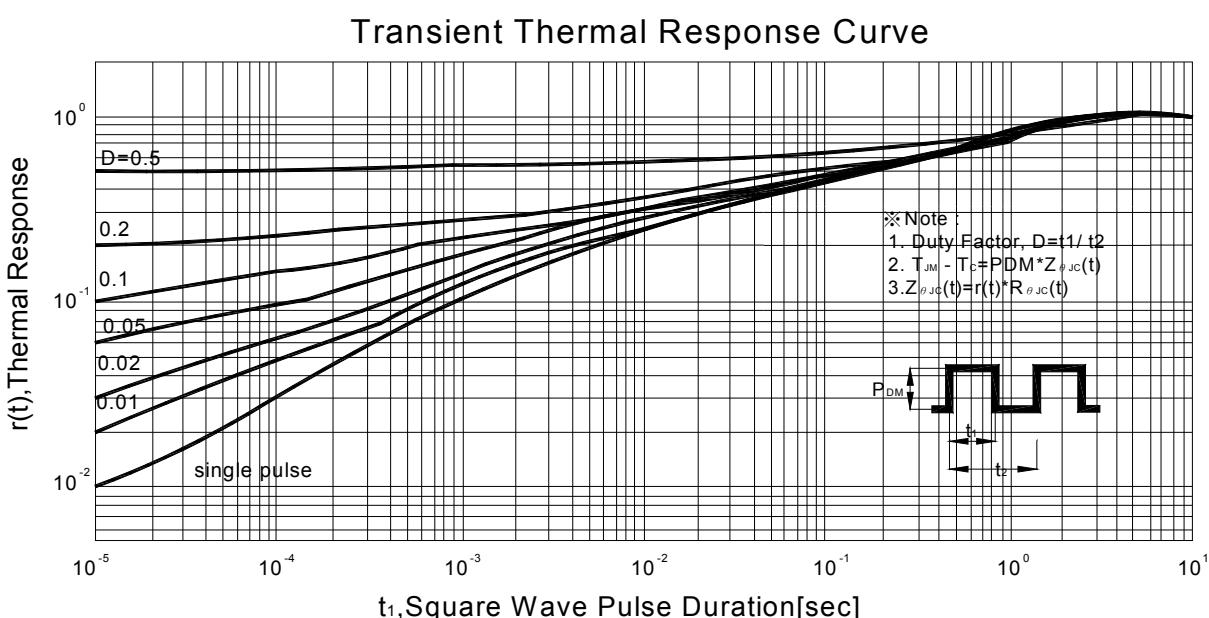
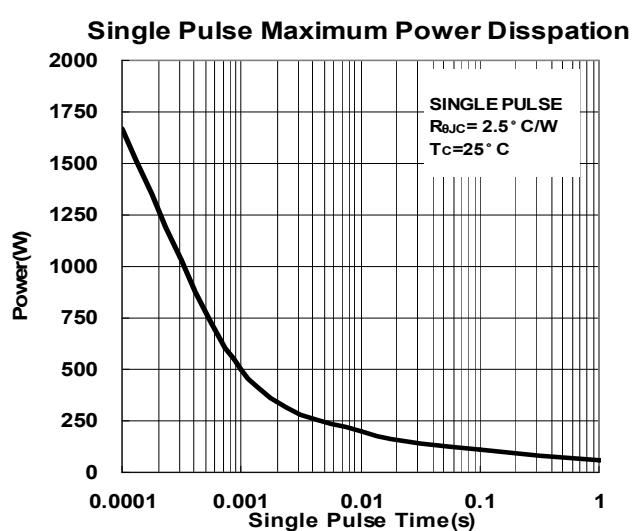
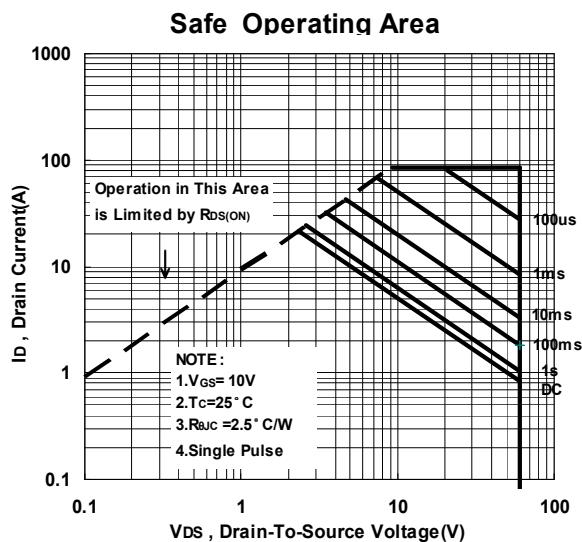
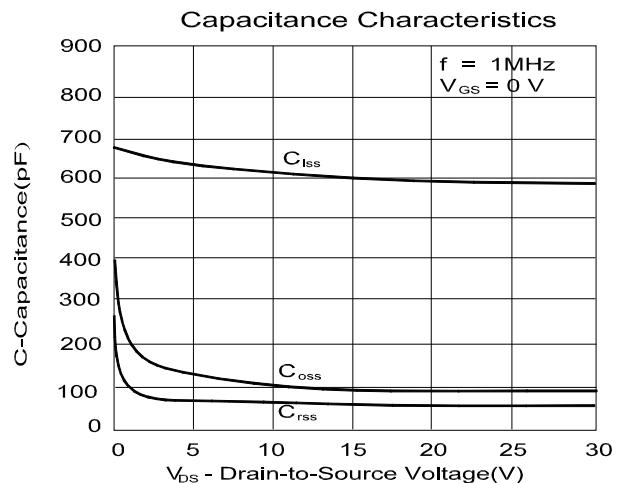
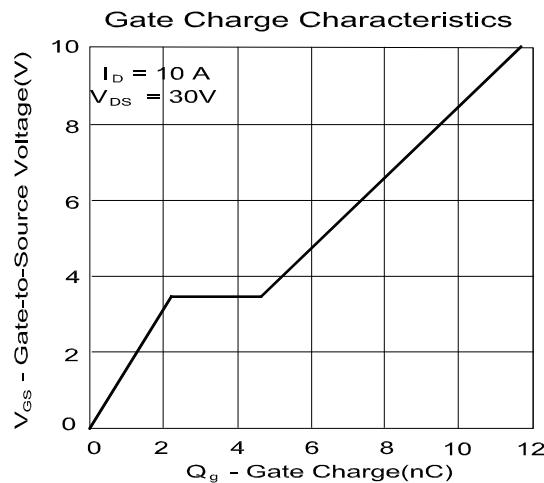
Drain-Source On-State Resistance <sup>1</sup>	R <sub>DS(ON)</sub>	V <sub>GS</sub> = 5V, I <sub>D</sub> = 8A	60	80	mΩ
		V <sub>GS</sub> = 10V, I <sub>D</sub> = 12A	48	60	
Forward Transconductance <sup>1</sup>	g <sub>fs</sub>	V <sub>DS</sub> = 10V, I <sub>D</sub> = 10A	12		S

DYNAMIC						
Input Capacitance	C <sub>iss</sub>			584		
Output Capacitance	C <sub>oss</sub>	V <sub>GS</sub> = 0V, V <sub>DS</sub> = 25V, f = 1MHz		79		pF
Reverse Transfer Capacitance	C <sub>rss</sub>			44		
Total Gate Charge <sup>2</sup>	Q <sub>g</sub>	V <sub>DS</sub> = 0.5V <sub>(BR)DSS</sub> , V <sub>GS</sub> = 10V, I <sub>D</sub> = 10A		11.5		
Gate-Source Charge <sup>2</sup>	Q <sub>gs</sub>			2.1		nC
Gate-Drain Charge <sup>2</sup>	Q <sub>gd</sub>			2.5		
Turn-On Delay Time <sup>2</sup>	t <sub>d(on)</sub>	V <sub>DD</sub> = 30V		10		
Rise Time <sup>2</sup>	t <sub>r</sub>	I <sub>D</sub> ≈ 1A, V <sub>GS</sub> = 10V, R <sub>GEN</sub> = 6Ω		7.3		
Turn-Off Delay Time <sup>2</sup>	t <sub>d(off)</sub>			17.5		nS
Fall Time <sup>2</sup>	t <sub>f</sub>			5.5		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (T <sub>c</sub> = 25 °C)						
Continuous Current	I <sub>s</sub>				12	A
Forward Voltage <sup>1</sup>	V <sub>SD</sub>	I <sub>F</sub> = I <sub>s</sub> , V <sub>GS</sub> = 0V			1.2	V

<sup>1</sup>Pulse test : Pulse Width ≤ 300 μsec, Duty Cycle ≤ 2%.<sup>2</sup>Independent of operating temperature.

REMARK: THE PRODUCT MARKED WITH "P6006BD", DATE CODE or LOT #

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## TO-252 (DPAK) MECHANICAL DATA

Dimension	mm			Dimension	mm		
	Min.	Typ.	Max.		Min.	Typ.	Max.
A	8.9	9.5	10.4	H	0.8	1.27	2.03
B	2.19	2.3	2.435	I	6.35	6.6	6.8
C	0.35	0.5	0.65	J	4.8	5.34	5.5
D	0.89		1.5	K	0.5		1.5
E	0.35		0.65	L	0.4	0.76	0.89
F	0.0		0.23	M	3.96		5.18
G	5.4		6.2	N			

